

## DIAL LONG LINE CIRCUIT SD-96588-01 TEST

### 1. GENERAL

**1.01** This section provides a method of testing the dial long line circuit using the associated test position. It also provides a procedure for taking the equipment out of service and the installation of a new unit.

**1.02** This issue affects the Equipment Test List.

**1.03** The following test is covered.

**PAGE**

**A. Loop Pulsing Test:** The loop pulsing test is made to check that the percent of break is below the specified maximum limit. . . . .

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### 2. APPARATUS

**2.01** Pulse repeating test set J34720A (SD-31667-01).

**2.02** Pulsing test set J34717A (SD 81481-01).

**2.03** Patching cords, two P2J cords, each 6 feet long, equipped with two 310 plugs (2P9B cords).

**2.04** Patching cord, P3E cord, 2 feet long, equipped with two 310 plugs (3P7D cord).

**2.05** Patching cords, two P3E cords, each 6 feet long, equipped with two 310 plugs (3P7A cord) (for input or output connections or both).

### 3. METHOD

STEP	ACTION	VERIFICATION
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**A. Loop Pulsing Test**

- |   |  |   |
|---|--|---|
| 1 | Obtain a spare unit.   |   |
| 2 | Determine condition of line (busy or idle).                              | L relay of unit in service nonoperated. |
| 3 | Remove unit from shelf.  |   |
| 4 | Insert spare unit in vacated shelf position.                             |   |
| 5 | Place unit under test in test position.                                  |   |
| 6 | Release TST and BAT keys.  |   |
| 7 | Operate BAT and TST keys when making pulse repeating tests.              |   |
| 8 | Connect pulse repeating test set to pulsing test set as shown in Fig. 1. |   |
| 9 | Connect pulse repeating test set to relay under test as shown in Fig. 1. |   |

STEP	ACTION	VERIFICATION
10	Set key selector on pulse repeating test set to apply 1200 ohms in series with pulsing contacts of pulsing test set.	
11	Read maximum percent break on output meter.	Circuit output 54 to 60 percent break.
12	Release TST and BAT keys and remove all test cords.	

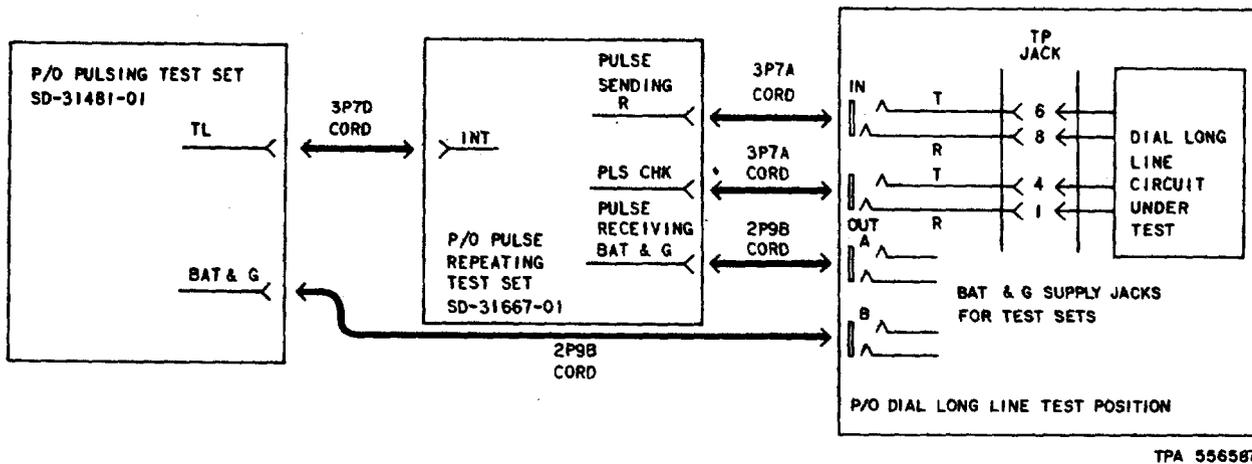


Fig. 1—Patching Requirements for Test Sets to Long Line Circuit